

## RELIABILITY MONITOR

**DS1232L OCT '98 MONITOR-HYUNDAI,KOREA**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232L	C1	9830	DL817678ABB	8 PIN SOIC	CHIPPAC, KOREA
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22755	INFANT LIFE	125°C, 7.0 VOLTS	232	48	HOUR	0
P22778	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22673	ULTRASOUND	J-STD-020	4	1	WEEK	3
TOTAL:						3
P22674	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22779	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22780	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P22781	AUTOCLAVE	121°C STEAM, UNBIASED	37	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1232L JAN '99 MONITOR-HYUNDAI,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232L	C2	9848	DL832093AAA	8 PIN SOIC	CHIPPAC, KOREA
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23139	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P23184	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P23062	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P23063	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235°C	238	3	PASS	0
TOTAL:						0
P23185	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P23186	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P23187	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1233Z OCT '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9836	DM819258ACA	SOT-223	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 μm Zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22753	INFANT LIFE	125°C, 7.0 VOLTS	229	48	HOUR	0
P22782	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P22675	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22676	HIGH TEMP STORAGE	125°C	233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	233	3	PASS	0
TOTAL:						0
P22783	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22784	HAST	120°C, 85%R.H.,5.5V	72	100	HOUR	0
TOTAL:						0
P22785	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1233 JAN '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9842	DM823017ABA	SOT-223	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 μm Zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23164	INFANT LIFE	125°C, 7.0 VOLTS	229	48	HOUR	0
P23250	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P23064	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P23065	HIGH TEMP STORAGE	125°C	233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	233	168	HOUR	
	CONVECTION REFLOW	235°C	233	3	PASS	0
TOTAL:						0
P23251	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P23252	HAST	120°C, 85%R.H.,5.5V	72	100	HOUR	0
TOTAL:						0
P23253	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1267 NOV '98 MONITOR-ANAM,PI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1267	A1	9823	DK803107AAE	20 PIN TSSOP	ANAM-PI (ATP/AAPI)
<b>PROCESS</b> Single Poly, Single Metal 1.2 μm Implanted poly1					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23026	INFANT LIFE	125°C, 6.0V,-4.0V	233	48	HOUR	0
TOTALS:			646	DEVICE HRS: 1.42E+06		0
P22790	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22791	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P23162	AUTOCLAVE	121°C STEAM, UNBIASED	37	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1302Z SEP '98 MONITOR-ANAM,PI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	A3	9829	DK817643ACA	8 PIN PDIP	ANAM-PI (ATP/AAPI)
<b>PROCESS</b> Single Poly, Double Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22691	INFANT LIFE	125°C, 6.0 VOLTS	234	48	HOUR	0
P22734	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
P22735	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22736	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22737	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1620S SEP '98 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	D1	9746	DJ711527ABD	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22599	INFANT LIFE	125°C, 7.0 VOLTS	230	48	HOUR	0
P22707	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P22500	ULTRASOUND	J-STD-020	4	2	WEEK	0
TOTAL:						0
P22501	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22708	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22709	HAST	120°C, 85%R.H.,5.5V	70	100	HOUR	0
TOTAL:						0
P22710	WRITE CYCLE STRESS	+85°C, 7.0 VOLTS	42	50	KCYC	0
		ELEC TEST	42	50	KCYC	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1620S SEP '98 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	D1	9746	DJ711527ABD	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23087	HIGH TEMP STORAGE	150°C	42	336	HOUR	0
			42	1000	HOUR	0
		ELEC TEST	42	1000	HOUR	0
		TOTAL:				0

## RELIABILITY MONITOR

**DS1803-010 NOV '98 MONITOR - HYUNDAI,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1803	A2	9833	DL820412AAB	16PN, 150 MIL SOIC	CHIPPAC, KOREA

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22797	ULTRASOUND	J-STD-020	4	1	WEEK	0
		TOTAL:				0
P22798	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
		TOTAL:				0

## RELIABILITY MONITOR

### DS2109 DEC '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2109	A7	9836	DM811524AA-	28 PIN SOIC	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23110	INFANT LIFE	125°C, 7.0 VOLTS	233	48	HOUR	0
P23155	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22902	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22903	HIGH TEMP STORAGE	125°C	237	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	237	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	237	3	PASS	0
TOTAL:						0
P23156	TEMP CYCLE	-55 TO 125°C	50	300	CYCL	0
			50	1000	CYCL	0
TOTAL:						0
P23157	HAST	120°C, 85%R.H.,5.5V	65	100	HOUR	0
TOTAL:						0
P23158	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2109S MAR '99 MONITOR-CARSEM**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2109	A7	9839	DM812688AAA	28 PIN SOIC	CARSEM

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23364	HIGH TEMP STORAGE	125°C	237	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	237	168	HOUR	
	CONVECTION REFLOW	235°C	237	3	PASS	0
	TOTAL:					0

## RELIABILITY MONITOR

**DS2118M MAR '99 MONITOR,D.P.-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2118M	A4	9904	DN844402AAC	36PN SSOP	ANAM-K (ASI/AICL)
<b>PROCESS</b> Single Poly, Double Metal 0.8 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23526	INFANT LIFE	125°C, 6.0 VOLTS	234	48	HOUR	0
TOTALS:			635	FAIL RATE (Fits): DEVICE HRS: 1.44E+06		0
P23366	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235°C	238	3	PASS	0
TOTAL:						0
P23602	HAST	130°C,85%R.H.,5.5V	77	100	HOUR	1
TOTAL:						1
P23603	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2153Q DEC '98 MONITOR-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9833	DN811539AAB	44 PIN PLCC	ANAM-K (ASI/AICL)
<b>PROCESS</b> Double Poly, Single Metal 0.8 μm Capacitor					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23108	INFANT LIFE	125°C, 6.0 VOLTS	237	48	HOUR	0
P23191	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			81	FAIL RATE (Fits): DEVICE HRS: 1.14E+07		0
P22904	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22905	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P23192	TEMP CYCLE	-55 TO 125°C	60	1000	CYCL	0
TOTAL:						0
P23193	AUTOCLAVE	121°C STEAM, UNBIASED	100	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2153Q MAR '99 MONITOR,D.P.-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9901	DN819185AAB	44 PIN PLCC	ANAM-K (ASI/AICL)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23368	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
		TOTAL:				0

## RELIABILITY MONITOR

**DS2165Q OCT '98 MONITOR - ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2165	B1	9837	DN811583AAB	28 PIN PLCC	ANAM-K (ASI/AICL)
<b>PROCESS</b> Single Poly, Single Metal 1.2 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22757	INFANT LIFE	125°C, 7.0 VOLTS	236	48	HOUR	0
TOTALS:			232	3.94E+06	DEVICE HRS:	0
P22680	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22681	TEMP CYCLE	-55 TO 125°C	241	10	CYCL	
	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P23171	AUTOCLAVE	121°C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2175 JAN '99 MONITOR-ANAM,PI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2175	D1	9838	DK826585AAC	16 PIN SOIC	ANAM-PI (ATP/AAPI)
<b>PROCESS</b> Single Poly, Single Metal 2.0 μm Pfield					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23183	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
TOTALS:			233	3.92E+06	DEVICE HRS:	0
P23069	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P23070	TEMP CYCLE	-55 TO 125°C	238	10	CYCL	
	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235°C	238	3	PASS	0
TOTAL:						0
P23234	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P23235	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P23236	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2181A AUG '98 MONITOR-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2181A	A2	9808	DN751456AAC	44 PIN PLCC	ANAM-K (ASI/AICL)
<b>PROCESS</b> Single Poly, Single Metal 2.0 μm Pfield					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22480	INFANT LIFE	125°C, 7.0 VOLTS	237	48	HOUR	0
P22918	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P22383	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22384	TEMP CYCLE	-55 TO 125°C	241	10	CYCL	
	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22919	TEMP CYCLE	-55 TO 125°C	60	300	CYCL	0
			60	1000	CYCL	0
TOTAL:						0
P22920	HAST	120°C, 85%R.H.,5.5V	48	100	HOUR	0
TOTAL:						0
P22921	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS21S07AE NOV '98 MONITOR - ANAM,PI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07A	B2	9825	DK809216ACB	20 PIN TSSOP	ANAM-PI (ATP/AAPI)
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22912	INFANT LIFE	125°C, 7.0 VOLTS	231	48	HOUR	0
P23127	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22799	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22800	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P23128	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P23130	AUTOCLAVE	121°C STEAM, UNBIASED	37	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS2401 DEC '98 TO-92 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9815	DM803085AAA	TO-92	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22922	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
		<b>TOTALS:</b>			<b>FAIL RATE (Fits):</b>	93
P22923	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
		<b>TOTAL:</b>				
P22924	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
		<b>TOTAL:</b>				
P22925	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
		<b>TOTAL:</b>				

## RELIABILITY MONITOR

### DS2401 DEC '98 TO92 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9815	DM803085AAA	TO-92	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22908	INFANT LIFE	125°C, 6.0 VOLTS	234	48	HOUR	0
TOTALS:			635	FAIL RATE (Fits): DEVICE HRS: 1.44E+06		0
P22923	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22924	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P22925	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS2401 MAR '99 TO-92 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	C2	9851	DM832008AIA	TO-92	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.6 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23371	INFANT LIFE	125°C, 6.0 VOLTS	234	48	HOUR	0
TOTALS:			635	FAIL RATE (Fits): DEVICE HRS: 1.44E+06		0
P23402	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P23403	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P23404	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS2434 NOV '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2434	D1	9827	DM809170AAA	TO-226 (PR-35)	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22801	INFANT LIFE	125°C, 7.0 VOLTS	237	48	HOUR	0
P22857	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.09E+07		0
P22858	TEMP CYCLE	-55 TO 125°C	50	300	CYCL	0
			50	1000	CYCL	0
TOTAL:						0
P22860	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS2502 OCT '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B6	9822	DM810309ACB	6 PIN TSOC	CARSEM

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22682	ULTRASOUND	J-STD-020	4	1	WEEK	0
		TOTAL:				0
P22683	HIGH TEMP STORAGE	125°C	151	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	151	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	151	3	PASS	0
		TOTAL:				0
P22741	TEMP CYCLE	-55 TO 125°C	77	300	CYCL	0
		-55 TO 125°C	77	1000	CYCL	0
		TOTAL:				0
P22742	AUTOCLAVE	121°C STEAM, UNBIASED	70	96	HOUR	0
		TOTAL:				0

## RELIABILITY MONITOR

### DS2502S DEC '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	C2	9842	DM821478AIB	8 PIN SOIC	CARSEM
<b>PROCESS</b> Double Poly, Single Metal 0.6 μm EPROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23041	INFANT LIFE	125°C, 7.0 VOLTS	228	48	HOUR	0
P23123	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P22909	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22910	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
	ELECTRICAL TEST	ELEC TEST	232	0		0
TOTAL:			232	0		0
P23124	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P23125	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS2502S DEC '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	C2	9842	DM821478AIB	8 PIN SOIC	CARSEM
<b>PROCESS</b> Double Poly, Single Metal 0.6 μm EPROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23126	HIGH TEMP STORAGE	150°C	34	336	HOUR	0
			34	1000	HOUR	0
<b>TOTAL:</b>						<b>0</b>

## RELIABILITY MONITOR

**DS2502 JAN '99 6PN TSOC MONITOR-CARSEM**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B6	9828	DM811456ADA	6 PIN TSOC	CARSEM

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23071	ULTRASOUND	J-STD-020	4	1	WEEK	0
		TOTAL:				0
P23072	HIGH TEMP STORAGE	125°C	151	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	151	168	HOUR	
	CONVECTION REFLOW	235°C	151	3	PASS	0
		TOTAL:				0
P23153	TEMP CYCLE	-55 TO 125°C	77	300	CYCL	0
		-55 TO 125°C	77	1000	CYCL	0
		TOTAL:				0
P23154	AUTOCLAVE	121°C STEAM, UNBIASED	68	96	HOUR	0
		TOTAL:				0

## RELIABILITY MONITOR

**DS5002 OCT '98 MONITOR,D.P.-CARSEM**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9831	DM817638AAF	80 PIN PQFP	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 μm Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22751	INFANT LIFE	125°C, 7.0 VOLTS	198	48	HOUR	0
P22769	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.02E+07		0
P22688	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22689	HIGH TEMP STORAGE	125°C	203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	203	3	PASS	0
TOTAL:						0
P22770	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22771	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
			42	959	HOUR	0
TOTAL:						0
P22772	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS5002 JAN '99 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9846	DM830493AAB	80 PIN PQFP	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 μm Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23122	INFANT LIFE	125°C, 7.0 VOLTS	199	48	HOUR	1
P23229	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	1
TOTALS:			104	FAIL RATE (Fits): 2.98E+07		2
P23073	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P23074	HIGH TEMP STORAGE	125°C	203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	203	3	PASS	0
TOTAL:						0
P23230	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P23232	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
P23122	RTRIP	IN PROCESS	IN PROCESS			

## RELIABILITY MONITOR

**DS5002 JAN '99 MONITOR,D.P.-CARSEM**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9846	DM830493AAB	80 PIN PQFP	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 μm Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23229	BATT LEAKAGE	VERY LARGE (2μA). FA IN PROCESS			IN PROCESS	

## RELIABILITY MONITOR

**DS80320 JAN '99 MONITOR - ANAM,PI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80C320	B5	9841	DK827694AAD	40 PIN PDIP	ANAM-PI (ATP/AAPI)
<b>PROCESS</b> Single Poly, Single Metal 0.8 μm Poly silicide					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23075	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P23223	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P23224	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P23225	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P23226	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS87520 NOV '98 MONITOR,D.P.-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS87C520	A13	9832	DN821500AAB	44 PIN PLCC	ANAM-K (ASI/AICL)
<b>PROCESS</b> Double Poly, Single Metal 0.8 μm EPROM process w/silicided poly(s)					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23309	INFANT LIFE	125°C, 7.0 VOLTS	236	48	HOUR	0
TOTALS:			231	FAIL RATE (Fits): DEVICE HRS: 3.96E+06		0
P22843	ULTRASOUND	J-STD-020	4	1	WEEK	0
TOTAL:						0
P22844	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	240	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0

## RELIABILITY MONITOR

**DS87520 FEB '99 MONITOR,D.P.-ANAM,K**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS87C520	A11	9838	DN825394AAB	44 PIN PLCC	ANAM-K (ASI/AICL)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P23306	ULTRASOUND	J-STD-020	4	1	WEEK	0
		TOTAL:				0
P23307	HIGH TEMP STORAGE	125°C	239	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	239	240	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	239	3	PASS	0
		TOTAL:				0